## Notice of References Cited

Application/Control No. 10/759,066	Applicant(s)/Patent Under Reexamination CHANG, WEN-HAN		
Examiner	Art Unit		
Adolfo Nino	2831	Page 1 of 1	

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,616,080	09-2003	Edwards et al.	242/378.1
	В	US-6,276,502	08-2001	Leyba et al.	174/69
	С	US-6,682,008	01-2004	Yeh, Ryan	242/378.1
	D	US-6,273,354	08-2001	Kovacik et al.	191/12.2R
	E	US-3,705,962	12-1972	Banister, Lionel W.	242/378.1
	F	US-6,199,674	03-2001	Liao, Sheng Hsin	191/12.4
	G	US-3,657,491	04-1972	Ryder et al.	191/12.2R
	Н	US-			
	1	US-			
	J	US-			
	κ	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	α					
	R					
	S					
	Т					

## NON-PATENT DOCUMENTS

.*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)	
	υ		
	v		
	w		
	х		

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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